

94/B



MS IF
PATENT
1248-0509P

IN THE U.S. PATENT AND TRADEMARK OFFICE

Applicant: Kumi MIYACHI et al. Confirmation: 3629
Appl. No.: 09/615,956 Group: 2133
Filed: July 13, 2000 Examiner: Esaw Abraham T.
For: SEMICONDUCTOR DEVICE HAVING INTEGRALLY
SEALED INTEGRATED CIRCUIT CHIPS ARRANGED
FOR IMPROVED TESTING

L E T T E R

MS IF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

March 4, 2005

Sir:

Attached hereto please find a Form PTO-1449 along with a Japanese Office Action.

Applicants respectfully request that the attached documents be placed in the application file pursuant to MPEP § 609(B)4.

If the Examiner has any questions concerning this application, the Examiner is requested to contact Robert W. Downs, Reg. No. 48,222 at (703) 205-8000 in the Washington, DC area.

If necessary, the Commissioner is hereby authorized in this, concurrent, and future replies, to charge payment or credit any overpayment to Deposit Account No. 02-2448 for any additional fee


Appl. No. 09/615,956

required under 37 C.F.R. §§ 1.16 or 1.17; particularly, extension of time fees.

Respectfully submitted,

BIRCH, STEWART, KOLASCH & BIRCH, LLP

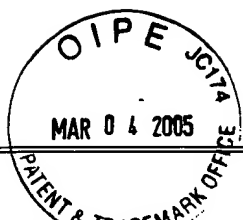
By


Charles Gorenstein
Reg. No. 29,271

RWD
CG/RWD/ph

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Falls Church, VA 22040-0747
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Attachments: Form PTO-1449
Japanese Office Action



Form PTO-1449

**INFORMATION DISCLOSURE CITATION
IN AN APPLICATION**

(Use several sheets if necessary)

ATTY. DOCKET NO.
1248-0509PAPPLICATION NO.
09/615,956APPLICANT
Kumi MIYACHI et al.FILING DATE
July 13, 2000GROUP
2133**U.S. PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NUMBER	Kind	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	US						
	US						
	US						
	US						
	US						
	US						
	US						
	US						
	US						
	US						

FOREIGN PATENT DOCUMENTS

	Office	DOCUMENT NUMBER	Kind	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION	
								YES	NO
	JP	06-066884		1994-03-11	JAPAN			Abs	

OTHER DOCUMENTS

(Include Name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published.

SAKAMAKI, Kazumi, Basic And Application of JTAG Test, CQ Publication, 12/1/98, p. 37.

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

RLD
CG/RWD